**Navigating Rice Seedling Cold Resilience: QTL Mapping in Two Inbred Line Populations and the Search for Genes**

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**Heading Date bins**

**Number of Plants**

**A**

Krasnodarskij 3352

WIR 911

Carolino 164

Carolino 164

**Supplementary FIGURE S1A.** Frequency distribution of heading date in F8:9 progeny of recombinant inbred lines derived from Krasnodarskij 3352 x Carolino 164 (RIL; left side), and in BC1F5:6 progeny of backcross recombinant inbred lines derived from [WIR 911 x Carolino 164] x Carolino 164 (BIL; right side). Arrows indicate the heading date values for the three parents.

**Plant Height (PTHT) [cm] bins**

**Number of Plants**

**B**

Krasnodarskij 3352

WIR 911

Carolino 164

Carolino 164

**Supplementary FIGURE S1B.** Frequency distribution of mature plant height (PTHT, measured in cm from soil level to tip of mature panicle) F8:9 progeny of recombinant inbred lines derived from Krasnodarskij 3352 x Carolino 164 (RIL; left side), and in BC1F5:6 progeny of backcross recombinant inbred lines derived from [WIR 911 x Carolino 164] x Carolino 164 (BIL; right side). Arrows indicate the PTHT values for the three parents.

**Percent Electrolyte Leakage (EL) bins**

**Number of Plants**

**C**

Krasnodarskij 3352

WIR 911

Carolino 164

Carolino 164

**Supplementary FIGURE S1C.** Frequency distribution of percent electrolyte leakage (EL) in leaves of F8:9 progeny of recombinant inbred lines derived from Krasnodarskij 3352 x Carolino 164 (RIL; left side), and in BC1F5:6 progeny of backcross recombinant inbred lines derived from [WIR 911 x Carolino 164] x Carolino 164 (BIL; right side) after a one-week exposure to constant 10°C. Arrows indicate the EL values for the three parents.

**Percent Low-Temperature Seedling Survivability (LTSS) bins**

**Number of Plants**

**D**

Krasnodarskij 3352

WIR 911

Carolino 164

Carolino 164

**Supplementary FIGURE S1D.** Frequency distribution of percent low-temperature seedling survivability (LTSS) of F8:9 progeny of recombinant inbred lines derived from Krasnodarskij 3352 x Carolino 164 (RIL; left side), and in BC1F5:6 progeny of backcross recombinant inbred lines derived from [WIR 911 x Carolino 164] x Carolino 164 (BIL; right side) after a one-week exposure to constant 10°C. Arrows indicate the LTSS values for the three parents.